



**ALPHA & OMEGA**  
SEMICONDUCTOR

**AOC2806**

**20V Common-Drain Dual N-Channel AlphaMOS**

### General Description

- Trench Power AlphaMOS (αMOS LV) technology
- Low  $R_{SS(ON)}$
- With ESD protection to improve battery performance and safety
- Common drain configuration for design simplicity
- RoHS and Halogen-Free Compliant

### Applications

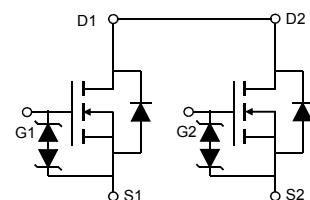
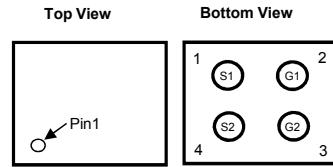
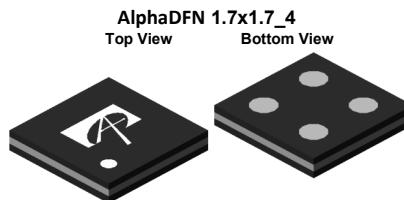
- Battery protection switch
- Mobile device battery charging and discharging

### Product Summary

$V_{SS}$	20V
$I_S$ (at $V_{GS}=4.5V$ )	4.5A
$R_{SS(ON)}$ (at $V_{GS}=4.5V$ )	< 18mΩ
$R_{SS(ON)}$ (at $V_{GS}=4.0V$ )	< 20mΩ
$R_{SS(ON)}$ (at $V_{GS}=3.7V$ )	< 21mΩ
$R_{SS(ON)}$ (at $V_{GS}=3.1V$ )	< 23mΩ
$R_{SS(ON)}$ (at $V_{GS}=2.5V$ )	< 29mΩ

### Typical ESD protection

HBM Class 3A



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOC2806	AlphaDFN 1.7x1.7_4	Tape & Reel	3000

### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Source-Source Voltage	$V_{SS}$	20	V
Gate-Source Voltage	$V_{GS}$	$\pm 12$	V
Source Current(DC) <sup>Note1</sup>	$I_S$   $T_A=25^\circ\text{C}$	4.5	A
Source Current(Pulse) <sup>Note2</sup>	$I_{SM}$	18	
Power Dissipation <sup>Note1</sup>	$P_D$   $T_A=25^\circ\text{C}$	0.7	W
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient	$t \leq 10\text{s}$	$R_{\theta JA}$	115	°C/W
Maximum Junction-to-Ambient	Steady-State		140	°C/W

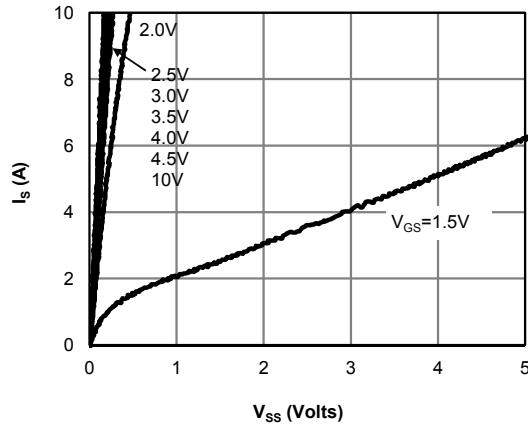
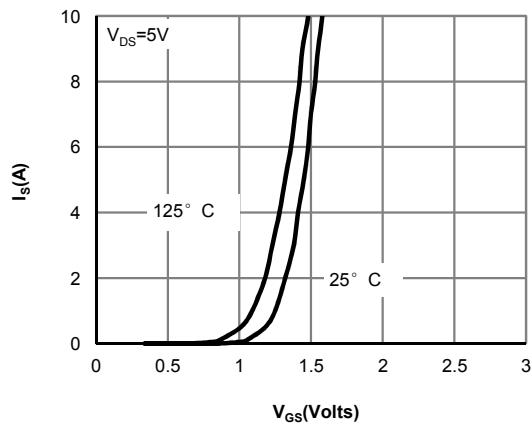
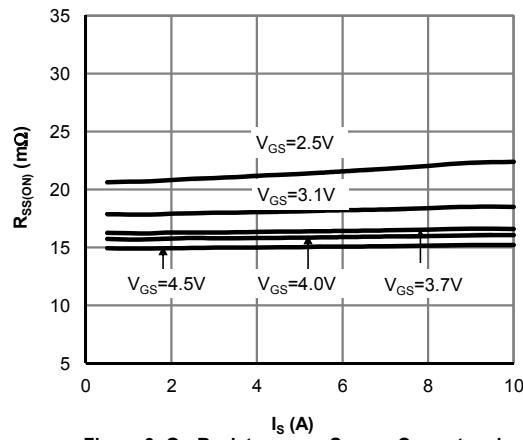
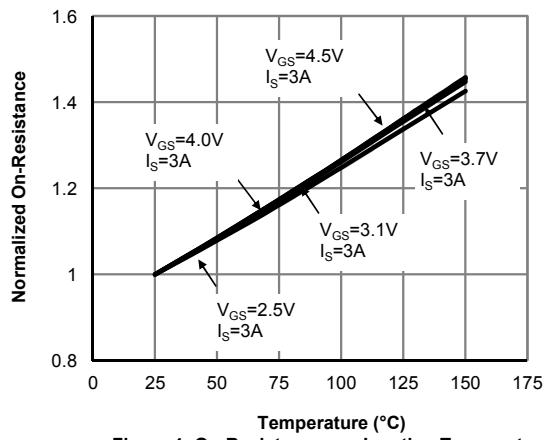
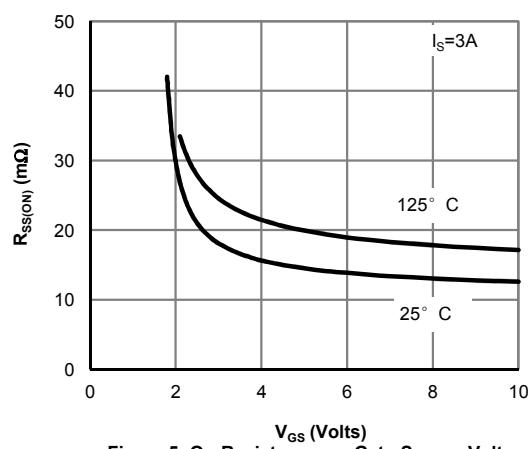
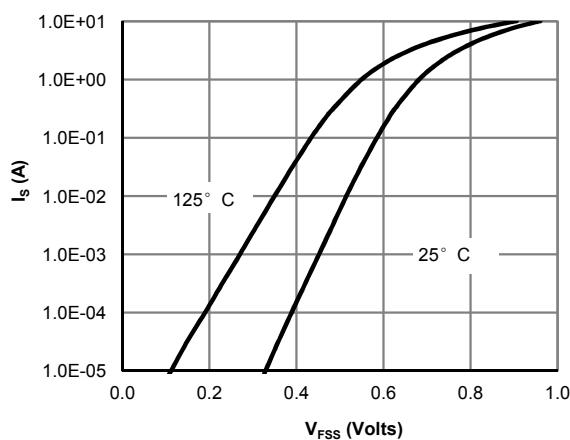
**Note 1.** Mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper.

**Note 2.** PW <300 μs pulses, duty cycle 0.5% max

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units	
<b>STATIC PARAMETERS</b>							
$\text{BV}_{\text{SSS}}$	Source-Source Breakdown Voltage	$I_S=250\mu\text{A}, V_{GS}=0\text{V}$	Test Circuit 6	20		V	
$I_{\text{SSS}}$	Zero Gate Voltage Source Current	$V_{SS}=20\text{V}, V_{GS}=0\text{V}$	Test Circuit 1		1	$\mu\text{A}$	
			$T_J=55^\circ\text{C}$		5		
$I_{GSS}$	Gate leakage current	$V_{SS}=0\text{V}, V_{GS}=\pm 10\text{V}$	Test Circuit 2		$\pm 10$	$\mu\text{A}$	
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{SS}=V_{GS}, I_S=250\mu\text{A}$	Test Circuit 3	0.5	0.85	1.3	V
$R_{SS(\text{ON})}$	Static Source to Source On-Resistance	$V_{GS}=4.5\text{V}, I_S=3\text{A}$	Test Circuit 4	10	15	18	$\text{m}\Omega$
		$T_J=125^\circ\text{C}$		14	20.5	25	
		$V_{GS}=4.0\text{V}, I_S=3\text{A}$	Test Circuit 4	11	15.8	20	$\text{m}\Omega$
		$V_{GS}=3.7\text{V}, I_S=3\text{A}$	Test Circuit 4	11.5	16.3	21	$\text{m}\Omega$
		$V_{GS}=3.1\text{V}, I_S=3\text{A}$	Test Circuit 4	12.5	17.6	23	$\text{m}\Omega$
$g_{FS}$	Forward Transconductance	$V_{SS}=5\text{V}, I_S=3\text{A}$	Test Circuit 4	14.5	21	29	$\text{m}\Omega$
			Test Circuit 3		16		
$V_{FSS}$	Forward Source to Source Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$	Test Circuit 5		0.68	1	V
<b>DYNAMIC PARAMETERS</b>							
$R_g$	Gate resistance	$f=1\text{MHz}$			2	$\text{k}\Omega$	
<b>SWITCHING PARAMETERS</b>							
$Q_g$	Total Gate Charge	$V_{G1S1}=4.5\text{V}, V_{SS}=10\text{V}, I_S=3\text{A}$		12.5		nC	
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{G1S1}=4.5\text{V}, V_{SS}=10\text{V}, R_L=3.3\Omega,$ $R_{\text{GEN}}=3\Omega$	Test Circuit 8	1.0		$\mu\text{s}$	
$t_r$	Turn-On Rise Time			3.0		$\mu\text{s}$	
$t_{D(\text{off})}$	Turn-Off DelayTime			2.1		$\mu\text{s}$	
$t_f$	Turn-Off Fall Time			8.8		$\mu\text{s}$	

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**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Figure 1: On-Region Characteristics**

**Figure 2: Transfer Characteristics**

**Figure 3: On-Resistance vs. Source Current and Gate Voltage**

**Figure 4: On-Resistance vs. Junction Temperature**

**Figure 5: On-Resistance vs. Gate-Source Voltage**

**Figure 6: Forward Source to Source Characteristics**

### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

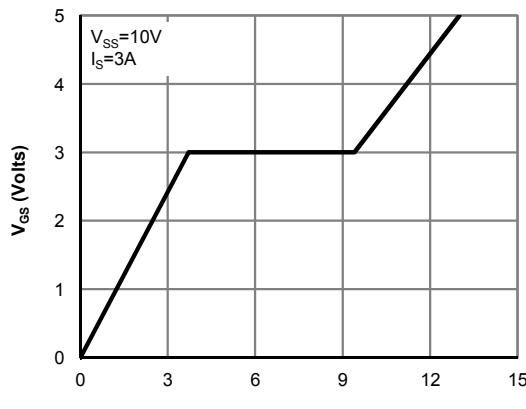
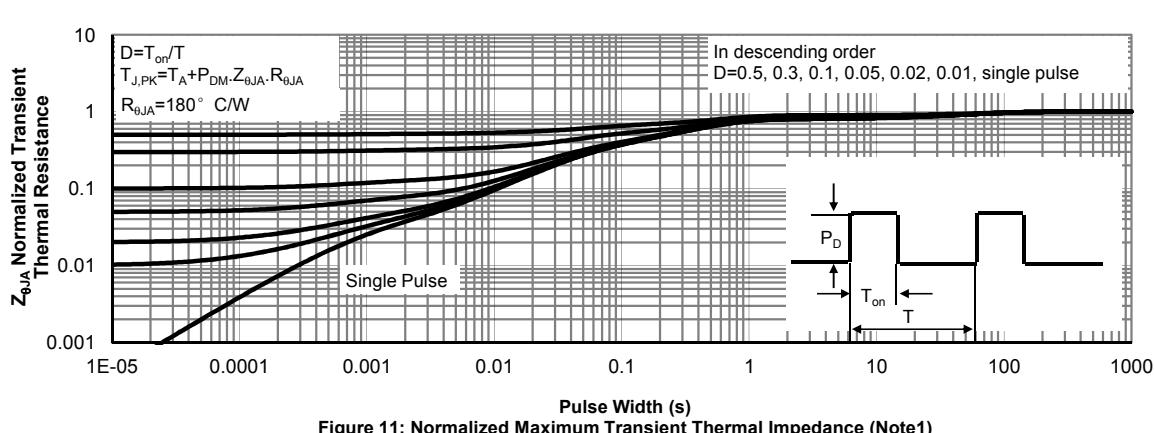
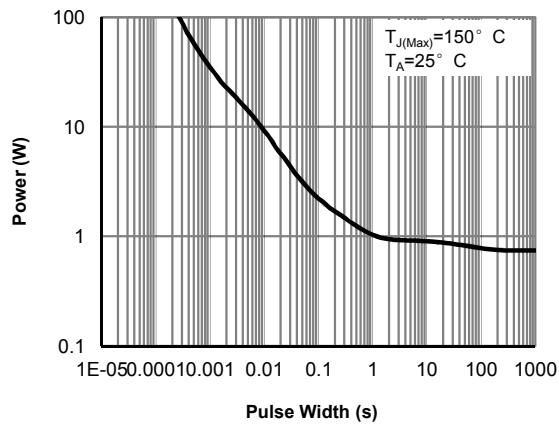
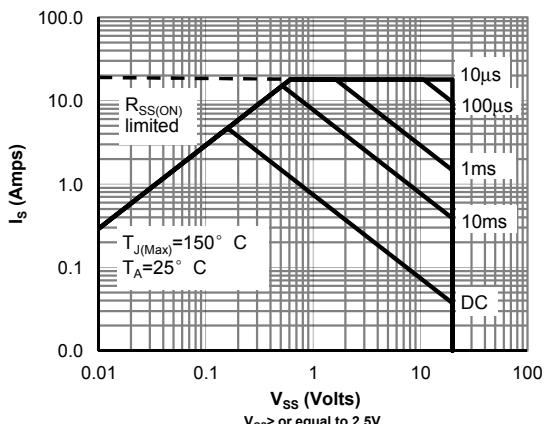
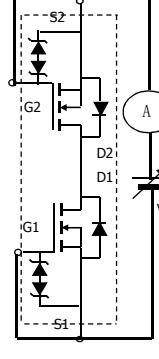
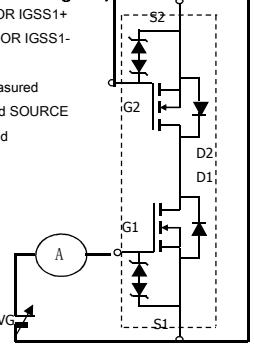
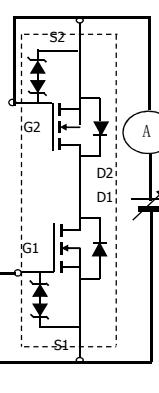
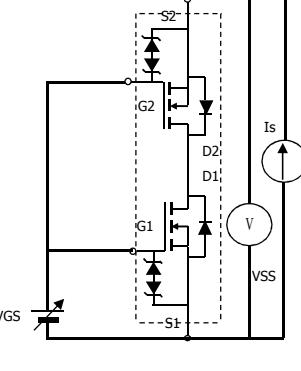
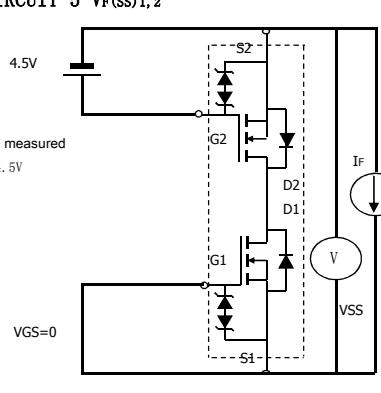
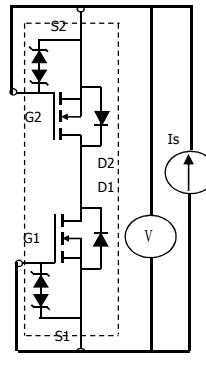
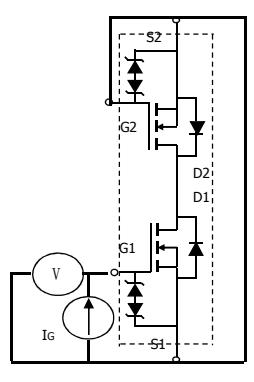


Figure 7: Gate-Charge Characteristics



<b>TEST CIRCUIT 1 Isss</b> POSITIVE VSS FOR ISSS+ NEGATIVE VSS FOR ISSS- 	<b>TEST CIRCUIT 2 Igss1,2</b> POSITIVE VGS FOR IGSS1+ NEGATIVE VGS FOR IGSS1- When FET1 is measured between GATE and SOURCE of FET2 are shorted 
<b>TEST CIRCUIT 3 Vgs(off)</b> When FET1 is measured between GATE and SOURCE of FET2 are shorted 	<b>TEST CIRCUIT 4 Rss(on)</b> 
<b>TEST CIRCUIT 5 VF(ss)1,2</b> When FET1 measured FET2 VGS=4.5V 	<b>TEST CIRCUIT 6 BVdss</b> POSITIVE VSS FOR ISSS+ NEGATIVE VSS FOR ISSS- 
<b>TEST CIRCUIT 7 BVgs01,2</b> POSITIVE VSS FOR ISSS+ NEGATIVE VSS FOR ISSS- When FET1 is measured between GATE and SOURCE of FET2 are shorted 	<b>TEST CIRCUIT 8 Switching time</b> 